

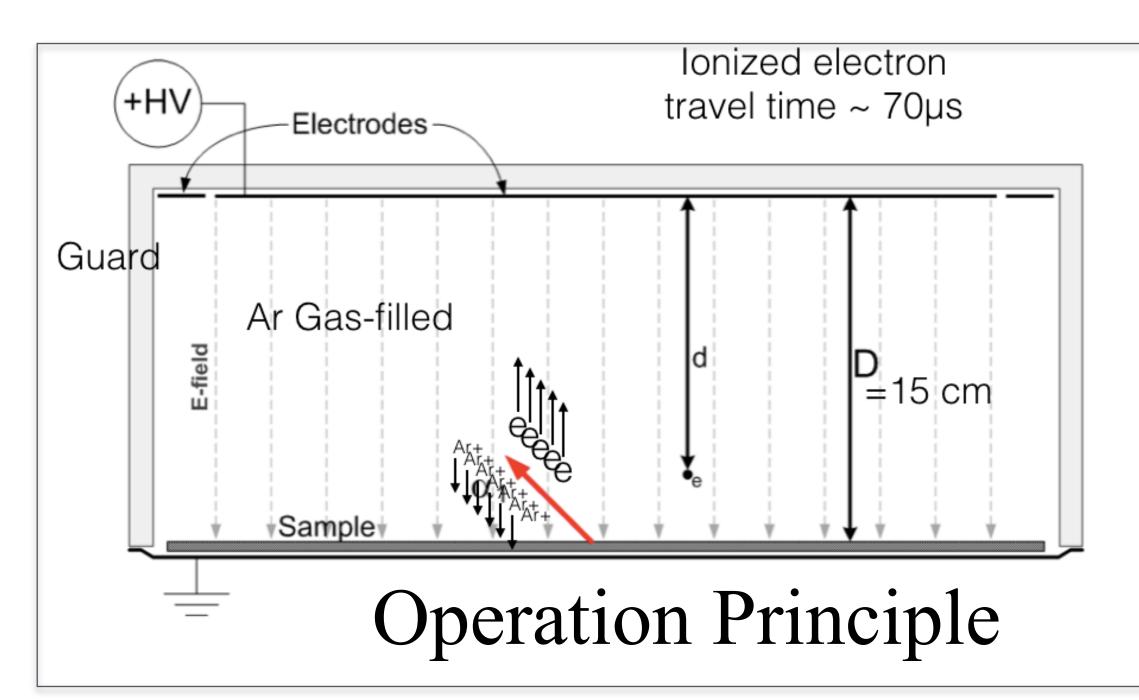
An Ar-gas ionization chamber for alpha particle detection at the Yangyang underground laboratory



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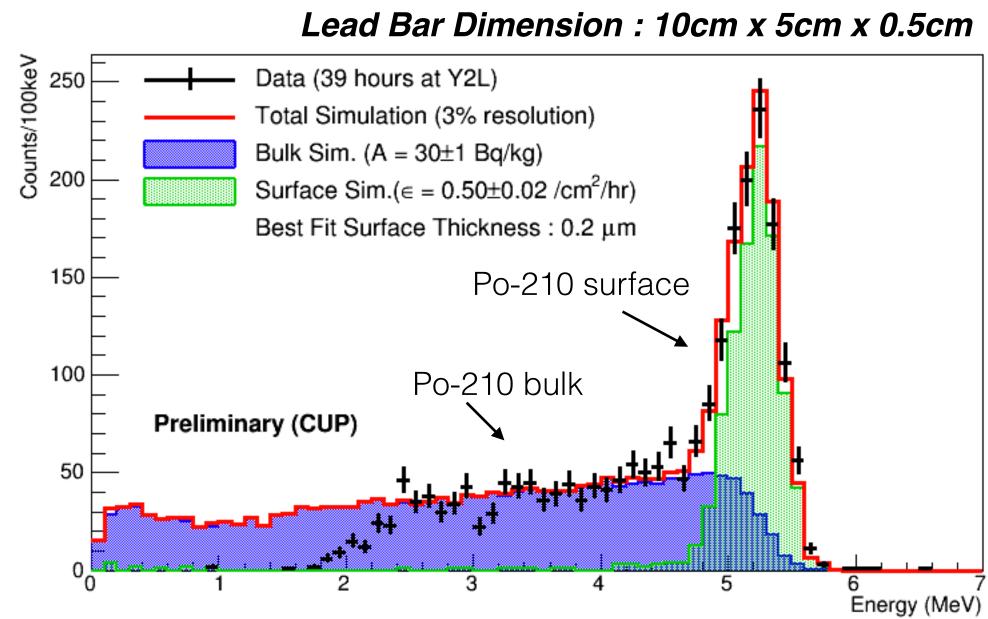
A high-sensitivity ionization detector for measuring alpha particles in a laminar sample has been operating in the Yangyang underground laboratory. The alpha counter is used to assay detector materials, especially their surface contamination, for the COSINE dark matter experiment and the AMoRE double beta decay experiment. Using distinct rise time, this instrument describes characteristic signals from ionization electrons produced from the sample tray and veto those from other sources. The detector can reach a sensitivity as low as 0.0001 count/cm^2/ hr.In this presentation, in addition to the low-background measurements, surface alpha measurements with various treatments such as cleaning and artificial contamination are reported.

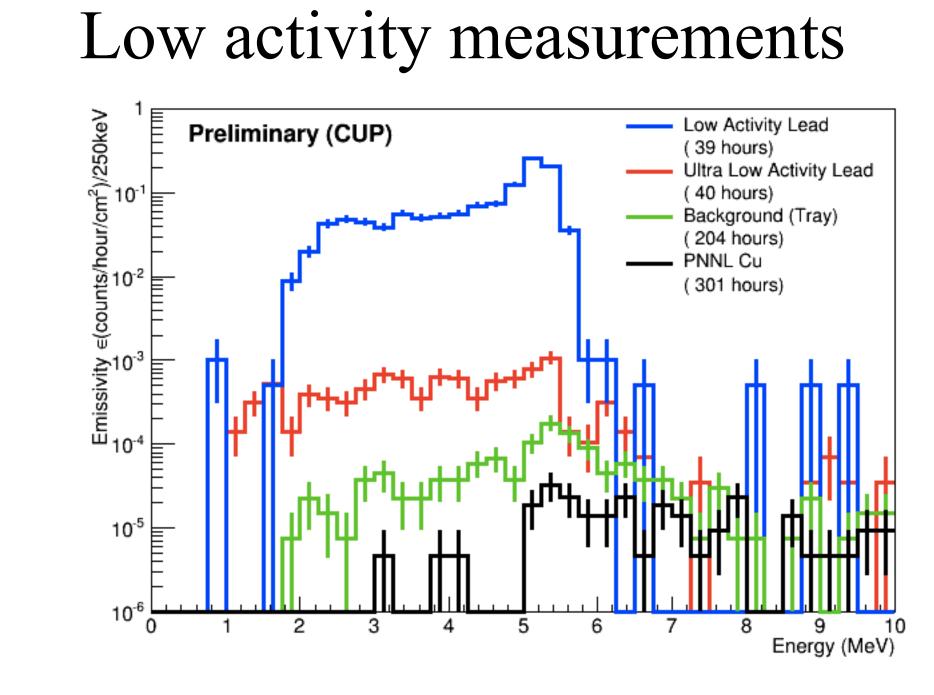




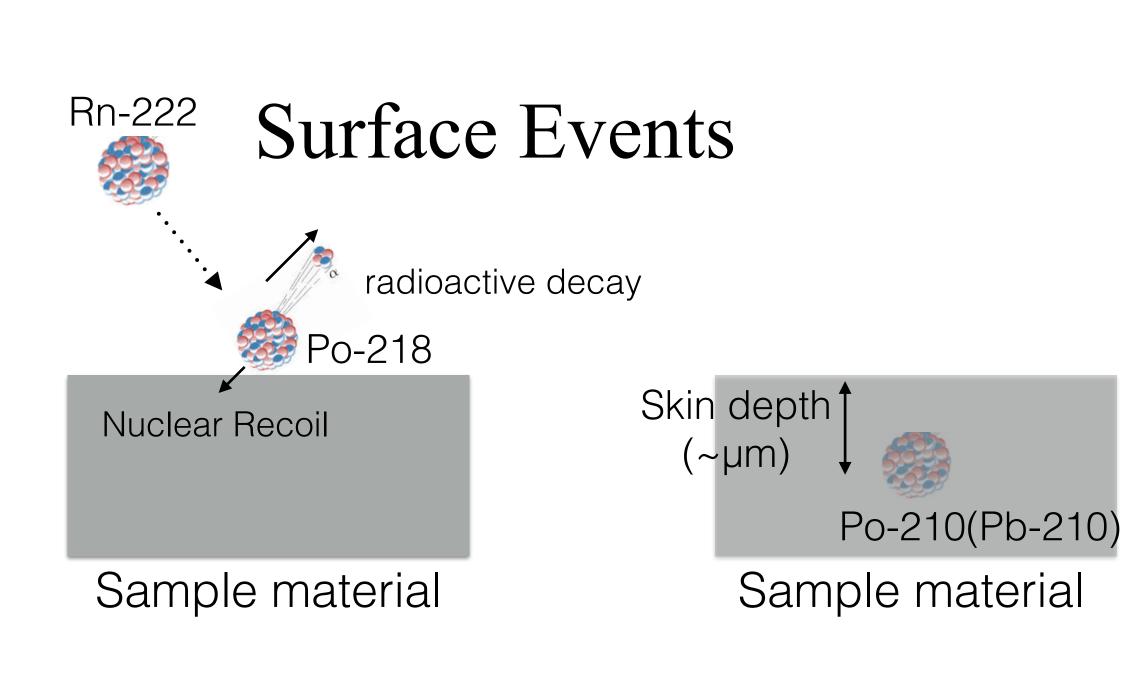


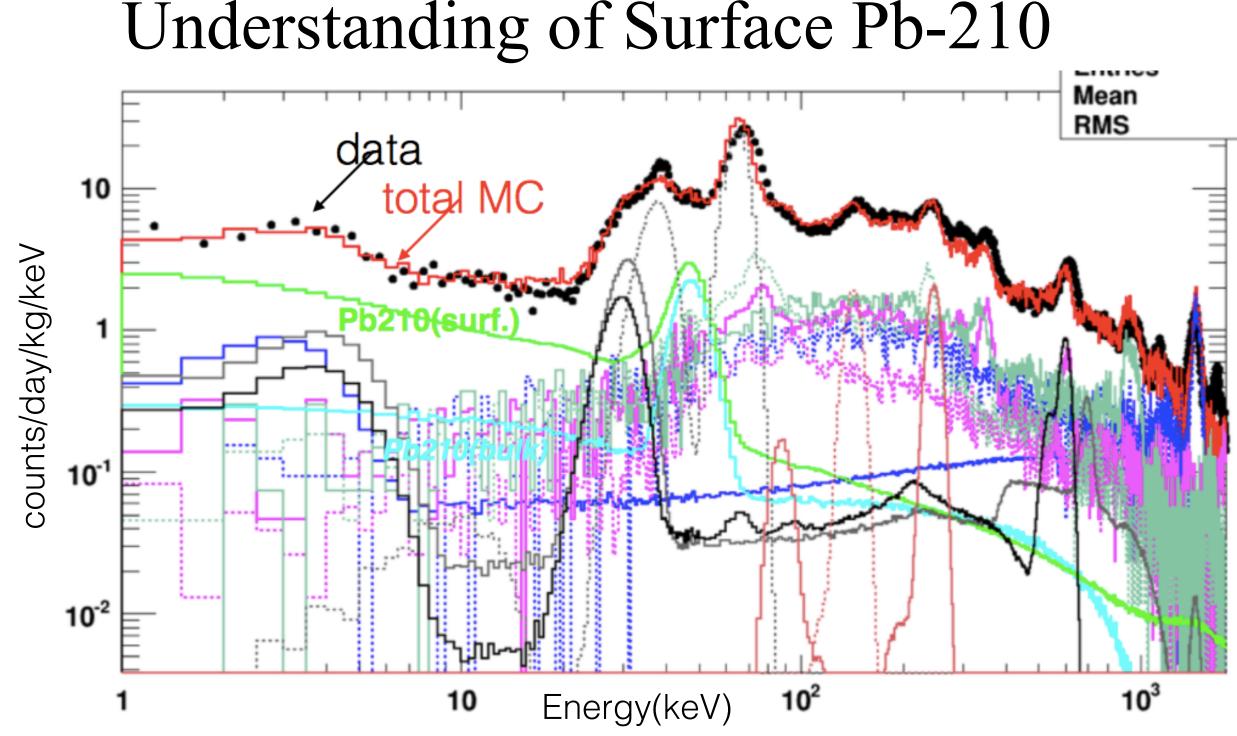
Calibration Am-241 source ONLY (A 10µm Mylar layer) source position Peak: 4.38±0.19 MeV (~5.5 MeV α decay) 9000 Am-241 source on a pyrex glass 8000 = Peak: 4.40±0.22 MeV Am-241 source on a pyrex glass at the edge 7000 Peak: 4.40±0.52 MeV 6000 ⊟ 5000 Preliminary (CUP) 4000 ⊟ 15cm 3000 2000 1000 sample tray Energy (MeV)



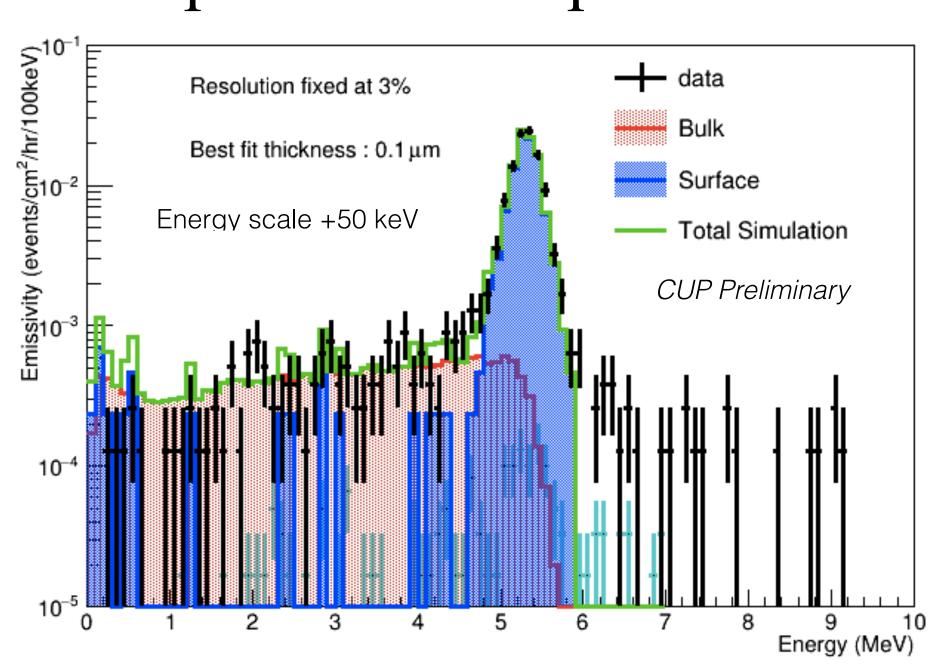


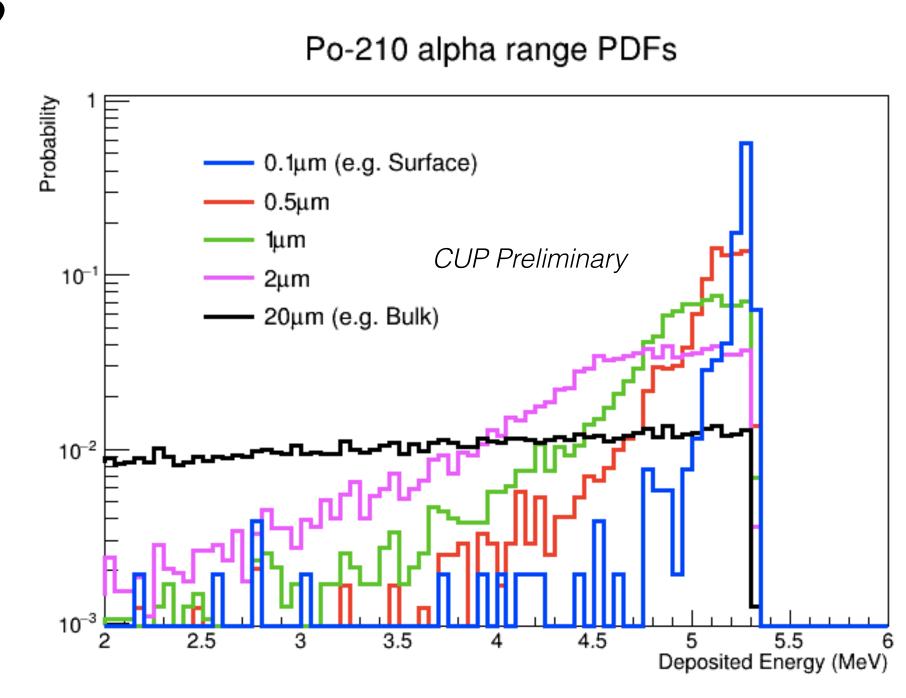
- Surface Alpha is critical to understand our main background
- Artificial contamination of Rn-222
- Penetration depth is estimated
- Cleaning study is on-going

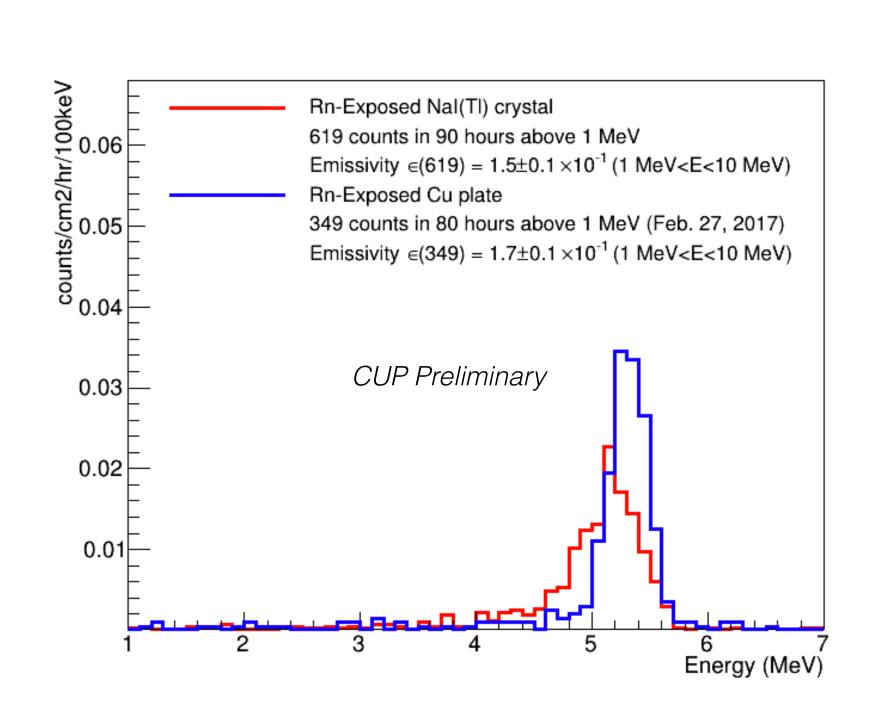




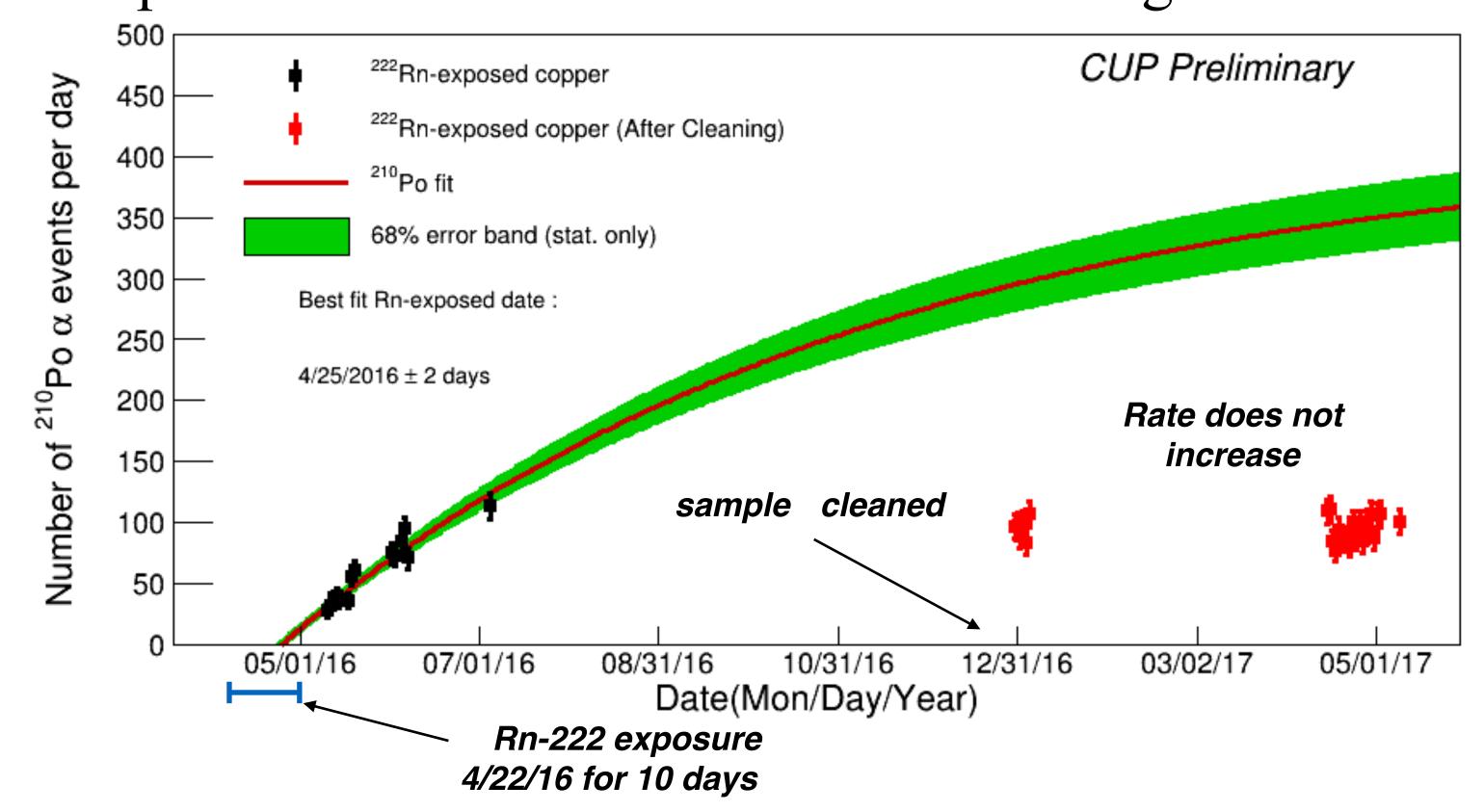
How deep can Po-210 penetrate in Cu?







Pinpoint contamination & Effect of cleaning with Rn-222



Summary

- An Ar ionization chamber alpha counter at Yangyang has been used to study surface contamination in the detector materials for rare event search detector experiments.
- Low activity samples including Cu plate and Nal powders are measured in the chamber.
- With a Rn-exposed Cu plate and a NaI(TI) crystal, we have been studying effect of surface contamination from a Rn-222 source.
- A maximum likelihood fit has been developed to extract surface contamination parameters from the ionization chamber alpha data.
- Sample treatment methods are also developed for removal of the surface contamination.